

Optimization the Thickness of the Free and Pinned Layers in a Spin-Valve Structure for High-field Sensitivity Planar Hall Effect Based Biochips

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Planar Hall effect (PHE) sensor using spin-valve structure has received much attention in biochip application due to its prominent advantages such as: high sensitivity, high signal-to-noise ratio, thermal stability, etc.. In this approach, we study the effect of the thickness of ferromagnetic (FM)-free and FM pinned layer in spin-valve structure on the role of the field sensitivity of the PHE sensor. The sensors with junction size of $50 \times 50 \mu\text{m}^2$ using spin-valve thin films Ta(5)/NiFe(x1)/Cu(1.5)/NiFe(x2)/IrMn(15)/Ta(5) with $x_1 = 4, 8, 10, 12, 16$ and $x_2 = 2, 3, 6, 8, 9, 12$ (nm) were fabricated successfully. The results show that the sensitivity of a PHE sensors is proportional to the thickness of FM free layer and inversely proportional to the thickness of FM pinned layer. The enhancement of the field-sensitivity is assumed by the enhancement of the active current passed through the FM free layer. The obtained results are explained well by using the Stoner-Wohlfarth energy, the theoretical calculations are in good agreement with experimental results.

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